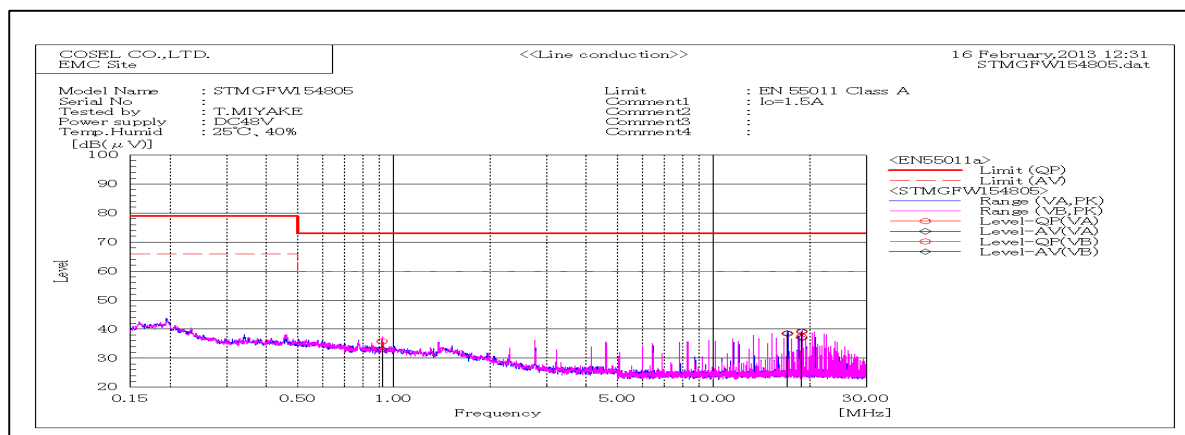
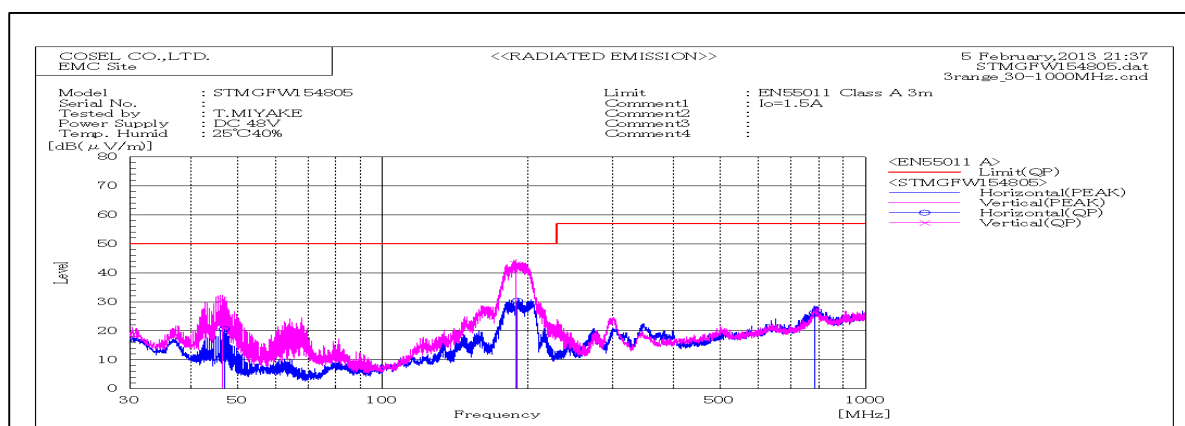


DATA SHEET		Date	18-Feb-13
Model	STMGFW154805	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Miyake



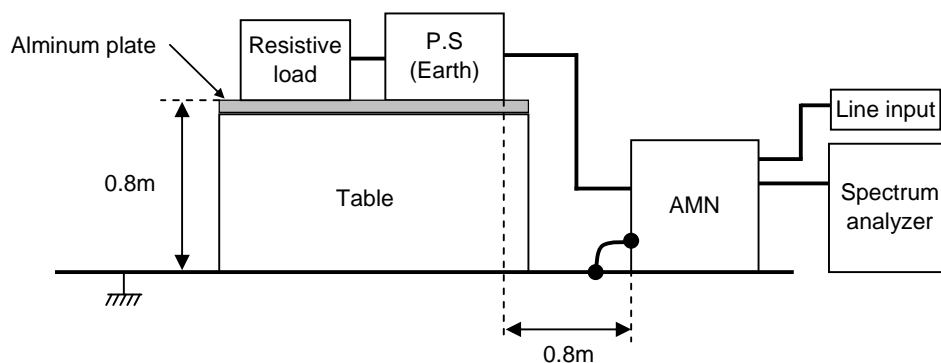
Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.91876		VB	15.7	13	20.1	35.8	33.1	73	60	37.2	26.9	Pass	
17.0375		VA	17.3	17.4	21.2	38.5	38.6	73	60	34.5	21.4	Pass	
18.88055		VB	17.9	17.9	21.2	39.1	39.2	73	60	33.9	20.8	Pass	
18.8766		VA	16.1	16.1	21.2	37.3	37	73	60	35.7	23	Pass	



Frequency MHz	Polarization	Stability	Reading dB(μV)		Space Loss dB	Level dB(mW)		Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	AV						
46.522	V	Stable	52.3		-21.5	30.8		50	19.2	Pass	101	305	
46.982	H	Stable	43.8		-23.2	20.6		50	29.4	Pass	154	103	
188.902	V	Stable	58.8		-15.8	43		50	7	Pass	105	284	
190.25	H	Stable	52.6		-22.3	30.3		50	19.7	Pass	156	50	
783.721	H	Stable	33.7		-7.6	26.1		57	30.9	Pass	103	77	

DATA SHEET		Date	18-Feb-13
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Miyake

## 1. Line conduction



## 2. Radiated emission

